

CPC**COOPERATIVE PATENT CLASSIFICATION****G01Q****SCANNING-PROBE TECHNIQUES OR APPARATUS; APPLICATIONS OF SCANNING-PROBE TECHNIQUES, e.g. SCANNING PROBE MICROSCOPY [SPM]****NOTE**

In this subclass, the first place priority rule is applied, i.e. at each hierarchical level, classification is made in the first appropriate place.

Guidance heading:**G01Q 10/00**

Scanning or positioning arrangements, i.e. arrangements for actively controlling the movement or position of the probe

G01Q 10/02

- . Coarse scanning or positioning

G01Q 10/04

- . Fine scanning or positioning

G01Q 10/045

- .. { Self-actuating probes, i.e. wherein the actuating means for driving are part of the probe itself, e.g. piezoelectric means on a cantilever probe }

G01Q 10/06

- .. Circuits or algorithms therefor

G01Q 10/065

- ... { Feedback mechanisms, i.e. wherein the signal for driving the probe is modified by a signal coming from the probe itself }

G01Q 20/00

Monitoring the movement or position of the probe

G01Q 20/02

- . by optical means

G01Q 20/04

- . Self-detecting probes, i.e. wherein the probe itself generates a signal representative of its position, e.g. piezo-electric gauge

G01Q 30/00

Auxiliary means serving to assist or improve the scanning probe techniques or apparatus, e.g. display or data processing devices

G01Q 30/02

- . Non-SPM analysing devices, e.g. SEM [Scanning Electron Microscope], spectrometer or optical microscope

G01Q 30/025

- .. { Optical microscopes coupled with SPM }

G01Q 30/04

- . Display or data processing devices

G01Q 30/06

- .. for error compensation

G01Q 30/08

- . Means for establishing or regulating a desired environmental condition within a sample chamber

G01Q 30/10

- .. Thermal environment

G01Q 30/12

- .. Fluid environment

G01Q 30/14	...	Liquid environment
G01Q 30/16	..	Vacuum environment
G01Q 30/18	.	Means for protecting or isolating the interior of a sample chamber from external environmental conditions or influences, e.g. vibrations or electromagnetic fields
G01Q 30/20	.	Sample handling device or method
G01Q 40/00		Calibration, e.g. of probes
G01Q 40/02	.	Calibration standards and methods of fabrication thereof
G01Q 60/00		Particular type of SPM [Scanning Probe Microscopy] or microscopes; Essential components thereof
G01Q 60/02	.	Multiple-type SPM, i.e. involving more than one SPM technique
G01Q 60/04	..	STM [Scanning Tunnelling Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/06	..	SNOM [Scanning Near-field Optical Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/08	..	MFM [Magnetic Force Microscopy] combined with AFM [Atomic Force Microscopy]
G01Q 60/10	.	STM [Scanning Tunnelling Microscopy] or apparatus therefor, e.g. STM probes
G01Q 60/12	..	STS [Scanning Tunnelling Spectroscopy]
G01Q 60/14	..	STP [Scanning Tunnelling Potentiometry]
G01Q 60/16	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/18	.	SNOM [Scanning Near-Field Optical Microscopy] or apparatus therefor, e.g. SNOM probes
G01Q 60/20	..	Fluorescence
G01Q 60/22	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/24	.	AFM [Atomic Force Microscopy] or apparatus therefor, e.g. AFM probes
G01Q 60/26	..	Friction force microscopy
G01Q 60/28	..	Adhesion force microscopy
G01Q 60/30	..	Scanning potential microscopy
G01Q 60/32	..	AC mode
G01Q 60/34	...	Tapping mode
G01Q 60/36	..	DC mode
G01Q 60/363	...	{ Contact-mode AFM }
G01Q 60/366	...	{ Nanoindenters, i.e. wherein the indenting force is measured }
G01Q 60/38	..	Probes, their manufacture, or their related instrumentation, e.g. holders
G01Q 60/40	...	Conductive probes
G01Q 60/42	...	Functionalization
G01Q 60/44	.	SICM [Scanning Ion-Conductance Microscopy] or apparatus therefor, e.g. SICM probes

- G01Q 60/46 . SCM [Scanning Capacitance Microscopy] or apparatus therefor, e.g. SCM probes
- G01Q 60/48 . . Probes, their manufacture, or their related instrumentation, e.g. holders
- G01Q 60/50 . MFM [Magnetic Force Microscopy] or apparatus therefor, e.g. MFM probes
- G01Q 60/52 . . Resonance
- G01Q 60/54 . . Probes, their manufacture, or their related instrumentation, e.g. holders
- G01Q 60/56 . . . Probes with magnetic coating
- G01Q 60/58 . SThM [Scanning Thermal Microscopy] or apparatus therefor, e.g. SThM probes
- G01Q 60/60 . SECM [Scanning Electro-Chemical Microscopy] or apparatus therefor, e.g. SECM probes
- G01Q 70/00** **General aspects of SPM probes, their manufacture or their related instrumentation, insofar as they are not specially adapted to a single SPM technique covered by group [G01Q 60/00](#)**
- G01Q 70/02 . Probe holders
- G01Q 70/04 . . with compensation for temperature or vibration induced errors
- G01Q 70/06 . Probe tip arrays
- G01Q 70/08 . Probe characteristics
- G01Q 70/10 . . Shape or taper
- G01Q 70/12 . . . Nano-tube tips
- G01Q 70/14 . . Particular materials
- G01Q 70/16 . Probe manufacture
- G01Q 70/18 . . Functionalization
- G01Q 80/00** **Applications, other than SPM, of scanning-probe techniques ([manufacture or treatment of nano-structures B82B 3/00](#); [recording or reproducing information using near-field interaction G11B 9/12](#), [G11B 11/24](#), [G11B 13/08](#))**
- G01Q 90/00** **Scanning-probe techniques or apparatus not otherwise provided for**